

*updated*

## Freeform Search

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**Database:** US Pre-Grant Publication Full-Text Database  
US Patents Full-Text Database  
US OCR Full-Text Database  
EPO Abstracts Database  
JPO Abstracts Database  
Derwent World Patents Index  
IBM Technical Disclosure Bulletins

**Term:** (near-field microscope) or (near-field probe)

**Display:** 10 Documents in Display Format: [-] Starting with Number [1]

**Generate:**  Hit List  Hit Count  Side by Side  Image

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**Search** **Clear** **Interrupt**

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### Search History

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**DATE:** Wednesday, March 16, 2005 [Printable Copy](#) [Create Case](#)

<u>Set Name</u>	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u>
side by side			result set
	DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
L3	(near-field microscope) or (near-field probe)	355	L3
	DB=PGPB,USPT,USOC,EPAB,JPAB; PLUR=YES; OP=ADJ		
L2	L1 and "near field"	389	L2
L1	(250/216,234,306,307,225,559.09;73/105;359/321,738 )![CCLS]	8752	L1

END OF SEARCH HISTORY